


<b>Search Notes</b>  	<b>Application/Control No.</b>  10585733	<b>Applicant(s)/Patent Under Reexamination</b>  ICHIKAWA, TAKESHI
	<b>Examiner</b>  SELIM AHMED	<b>Art Unit</b>  2826

SEARCHED			
Class	Subclass	Date	Examiner
438	57, 59, 60, 73, 78	11/9/08	/sa/
257	291, 292	11/9/08	/sa/
	Updated search	6/7/2009	/sa/

SEARCH NOTES		
Search Notes	Date	Examiner
Test search such as, buried channel, surface channel, image sensor, CMOS sensor, photoelectric, pixel, transistor, substrate and their boolean combinations were searched.	11/9/08	/sa/
Updated search	6/7/2009	/sa/

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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